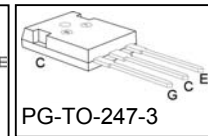
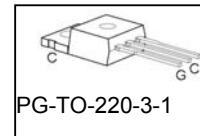
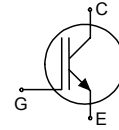


## Fast IGBT in NPT-technology

- 40% lower  $E_{off}$  compared to previous generation
- Short circuit withstand time – 10  $\mu$ s
- Designed for:
  - Motor controls
  - Inverter
  - SMPS
- NPT-Technology offers:
  - very tight parameter distribution
  - high ruggedness, temperature stable behaviour
  - parallel switching capability



- Qualified according to JEDEC<sup>1</sup> for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models : <http://www.infineon.com/igbt/>

Type	$V_{CE}$	$I_C$	$E_{off}$	$T_j$	Marking	Package
SGP15N120	1200V	15A	1.5mJ	150°C	GP15N120	PG-TO-220-3-1
SGW15N120	1200V	15A	1.5mJ	150°C	SGW15N120	PG-TO-247-3

### Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CE}$	1200	V
DC collector current	$I_C$		A
$T_C = 25^\circ\text{C}$		30	
$T_C = 100^\circ\text{C}$		15	
Pulsed collector current, $t_p$ limited by $T_{jmax}$	$I_{Cpuls}$	52	
Turn off safe operating area	-	52	
$V_{CE} \leq 1200\text{V}$ , $T_j \leq 150^\circ\text{C}$			
Gate-emitter voltage	$V_{GE}$	$\pm 20$	V
Avalanche energy, single pulse	$E_{AS}$	85	mJ
$I_C = 15\text{A}$ , $V_{CC} = 50\text{V}$ , $R_{GE} = 25\Omega$ , start at $T_j = 25^\circ\text{C}$			
Short circuit withstand time <sup>2</sup>	$t_{SC}$	10	$\mu$ s
$V_{GE} = 15\text{V}$ , $100\text{V} \leq V_{CC} \leq 1200\text{V}$ , $T_j \leq 150^\circ\text{C}$			
Power dissipation	$P_{tot}$	198	W
$T_C = 25^\circ\text{C}$			
Operating junction and storage temperature	$T_j$ , $T_{stg}$	-55...+150	$^\circ\text{C}$
Soldering temperature, 1.6mm (0.063 in.) from case for 10s	-	260	

<sup>1</sup> J-STD-020 and JESD-022

<sup>2</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.

### Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
<b>Characteristic</b>				
IGBT thermal resistance, junction – case	$R_{thJC}$		0.63	K/W
Thermal resistance, junction – ambient	$R_{thJA}$	PG-TO-220-3-1 PG-TO-247-3	62 40	

### Electrical Characteristic, at $T_j = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>Static Characteristic</b>						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V$ , $I_C=1000\mu A$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE} = 15V$ , $I_C=15A$ $T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	2.5 -	3.1 3.7	3.6 4.3	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=600\mu A$ , $V_{CE}=V_{GE}$	3	4	5	
Zero gate voltage collector current	$I_{CES}$	$V_{CE}=1200V$ , $V_{GE}=0V$ $T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	- -	- -	200 800	$\mu A$
Gate-emitter leakage current	$I_{GES}$	$V_{CE}=0V$ , $V_{GE}=20V$	-	-	100	nA
Transconductance	$g_{fs}$	$V_{CE}=20V$ , $I_C=15A$		11	-	S
<b>Dynamic Characteristic</b>						
Input capacitance	$C_{iss}$	$V_{CE}=25V$ , $V_{GE}=0V$ , $f=1\text{MHz}$	-	1250	1500	pF
Output capacitance	$C_{oss}$		-	100	120	
Reverse transfer capacitance	$C_{riss}$		-	65	80	
Gate charge	$Q_{Gate}$	$V_{CC}=960V$ , $I_C=15A$ $V_{GE}=15V$	-	130	175	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	$L_E$	PG-TO-220-3-1 PG-TO-247-3	-	7 13	-	nH
Short circuit collector current <sup>2)</sup>	$I_{C(SC)}$	$V_{GE}=15V$ , $t_{SC}\leq 5\mu s$ $100V\leq V_{CC}\leq 1200V$ , $T_j\leq 150^\circ\text{C}$	-	145	-	A

<sup>2)</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.

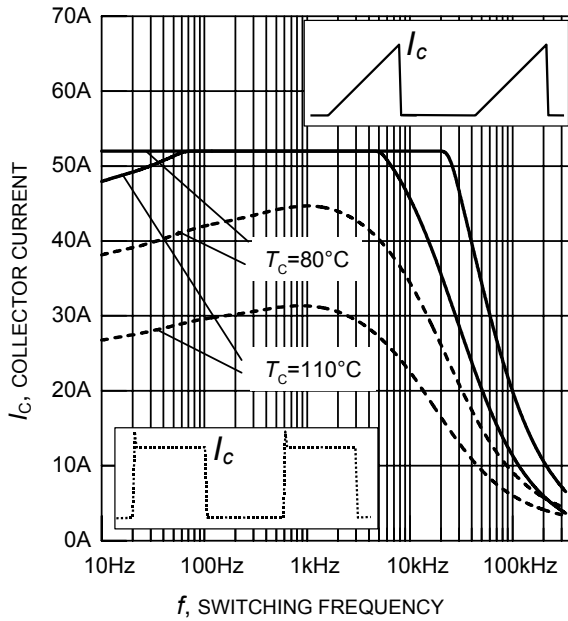
### Switching Characteristic, Inductive Load, at $T_j=25^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(\text{on})}$	$T_j=25^\circ\text{C}$ ,	-	18	24	ns
Rise time	$t_r$	$V_{\text{CC}}=800\text{V}$ , $I_C=15\text{A}$ ,	-	23	30	
Turn-off delay time	$t_{d(\text{off})}$	$V_{\text{GE}}=15\text{V}/0\text{V}$ ,	-	580	750	
Fall time	$t_f$	$R_G=33\Omega$ ,	-	22	29	
Turn-on energy	$E_{\text{on}}$	$L_{\sigma}^{(1)}=180\text{nH}$ ,	-	1.1	1.5	mJ
Turn-off energy	$E_{\text{off}}$	$C_{\sigma}^{(1)}=40\text{pF}$	-	0.8	1.1	
Total switching energy	$E_{\text{ts}}$	Energy losses include "tail" and diode reverse recovery.	-	1.9	2.6	

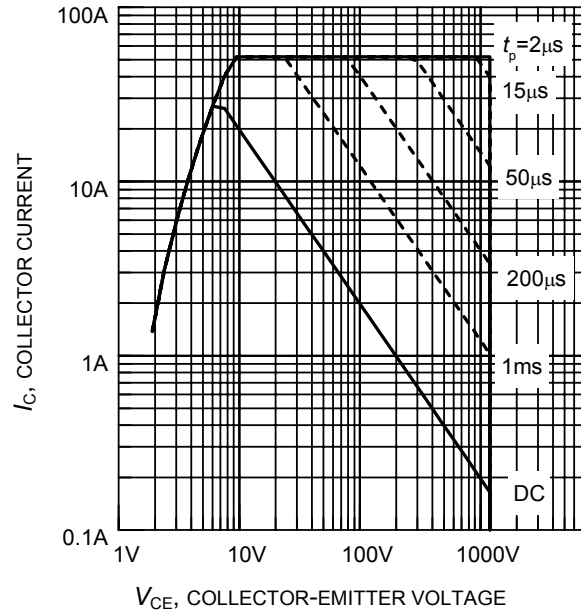
### Switching Characteristic, Inductive Load, at $T_j=150^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
<b>IGBT Characteristic</b>						
Turn-on delay time	$t_{d(\text{on})}$	$T_j=150^\circ\text{C}$	-	38	46	ns
Rise time	$t_r$	$V_{\text{CC}}=800\text{V}$ ,	-	30	36	
Turn-off delay time	$t_{d(\text{off})}$	$I_C=15\text{A}$ ,	-	652	780	
Fall time	$t_f$	$V_{\text{GE}}=15\text{V}/0\text{V}$ ,	-	31	37	
Turn-on energy	$E_{\text{on}}$	$R_G=33\Omega$ ,	-	1.9	2.3	mJ
Turn-off energy	$E_{\text{off}}$	$L_{\sigma}^{(1)}=180\text{nH}$ ,	-	1.5	2.0	
Total switching energy	$E_{\text{ts}}$	$C_{\sigma}^{(1)}=40\text{pF}$ Energy losses include "tail" and diode reverse recovery.	-	3.4	4.3	

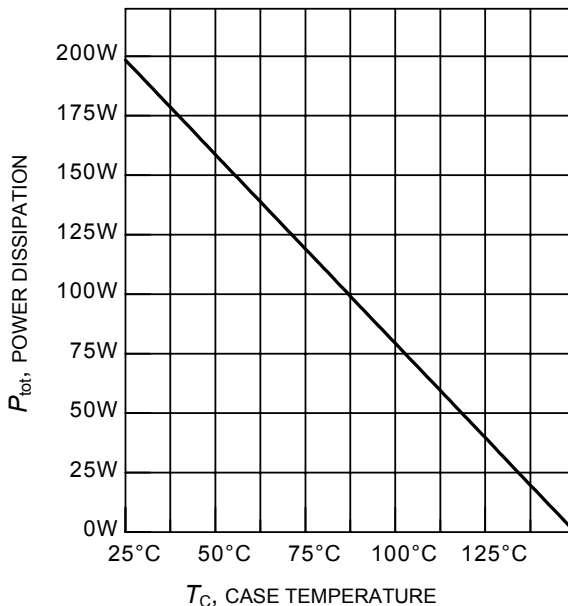
<sup>1)</sup> Leakage inductance  $L_{\sigma}$  and stray capacity  $C_{\sigma}$  due to dynamic test circuit in figure E.



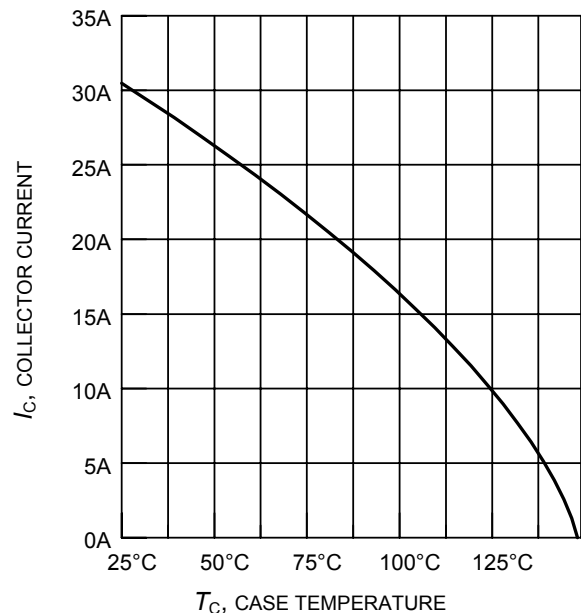
**Figure 1. Collector current as a function of switching frequency**  
 ( $T_j \leq 150^\circ\text{C}$ ,  $D = 0.5$ ,  $V_{CE} = 800\text{V}$ ,  
 $V_{GE} = +15\text{V}/0\text{V}$ ,  $R_G = 33\Omega$ )



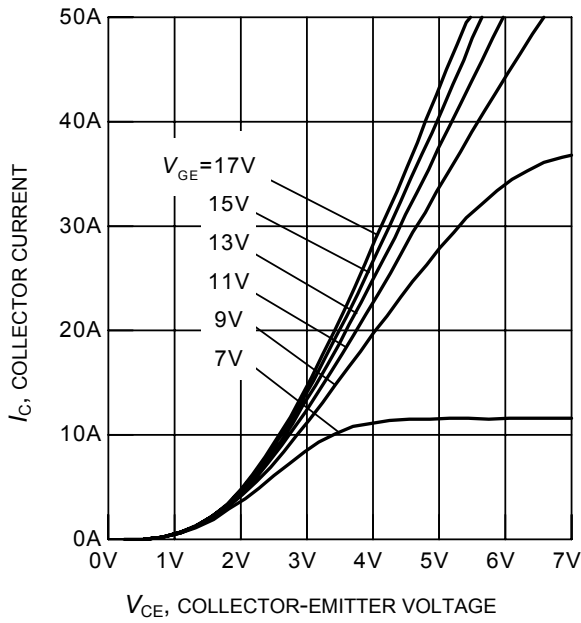
**Figure 2. Safe operating area**  
 ( $D = 0$ ,  $T_C = 25^\circ\text{C}$ ,  $T_j \leq 150^\circ\text{C}$ )



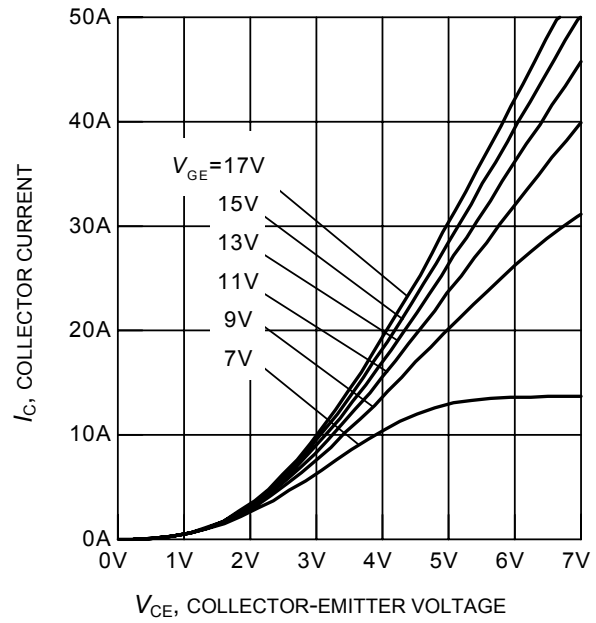
**Figure 3. Power dissipation as a function of case temperature**  
 ( $T_j \leq 150^\circ\text{C}$ )



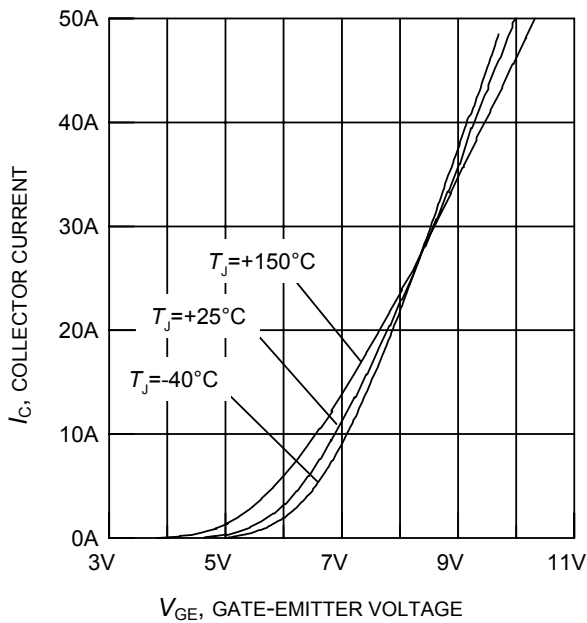
**Figure 4. Collector current as a function of case temperature**  
 ( $V_{GE} \leq 15\text{V}$ ,  $T_j \leq 150^\circ\text{C}$ )



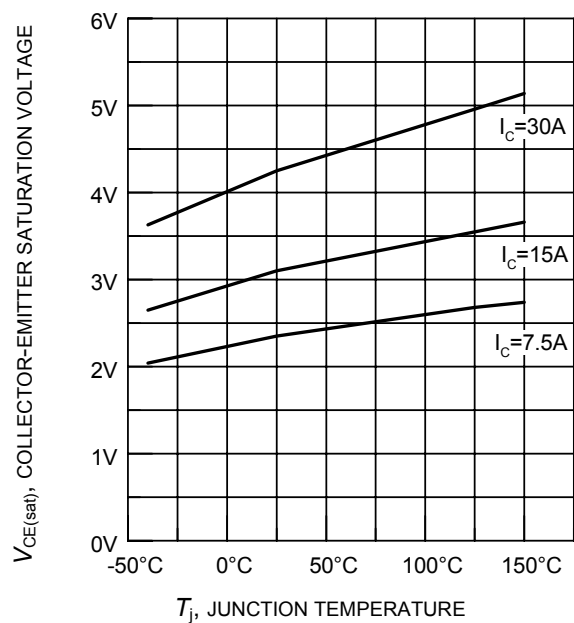
**Figure 5. Typical output characteristics**  
( $T_j = 25^\circ\text{C}$ )



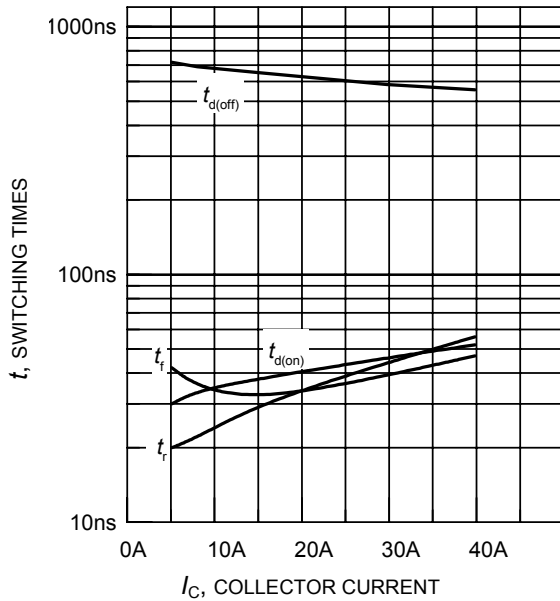
**Figure 6. Typical output characteristics**  
( $T_j = 150^\circ\text{C}$ )



**Figure 7. Typical transfer characteristics**  
( $V_{CE} = 20\text{V}$ )

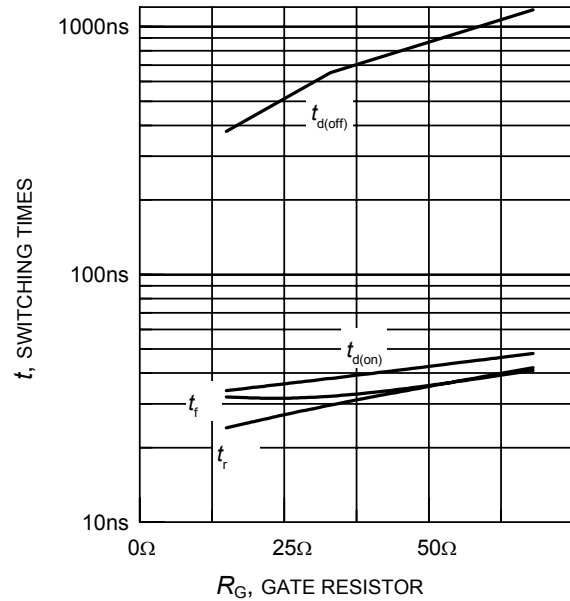


**Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature**  
( $V_{GE} = 15\text{V}$ )



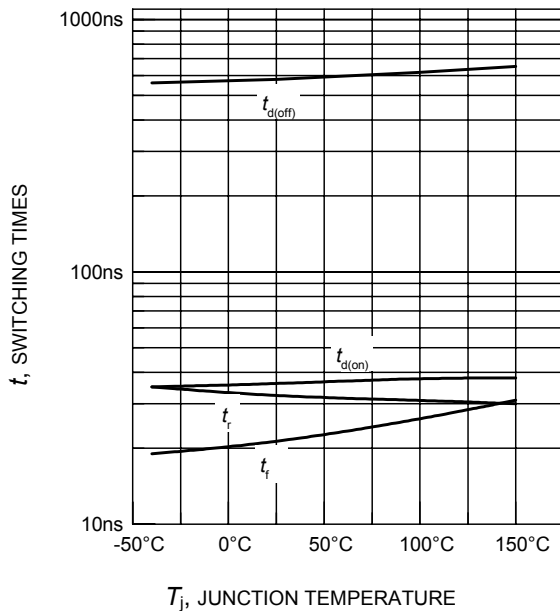
**Figure 9. Typical switching times as a function of collector current**

(inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $R_G = 33\Omega$ , dynamic test circuit in Fig.E )



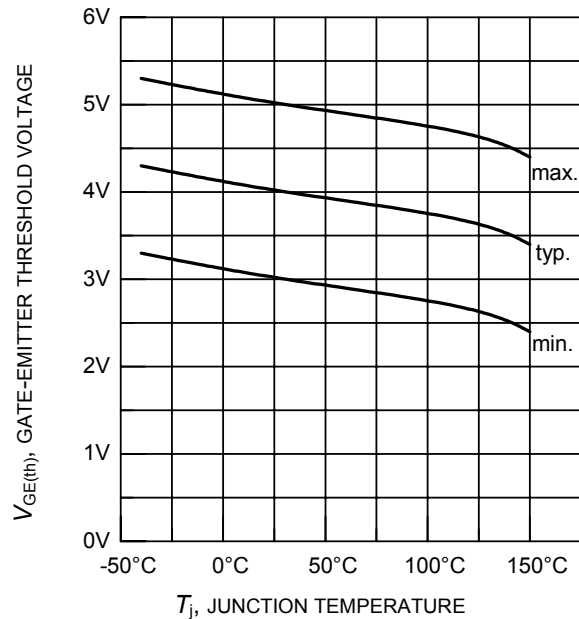
**Figure 10. Typical switching times as a function of gate resistor**

(inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 15\text{A}$ , dynamic test circuit in Fig.E )



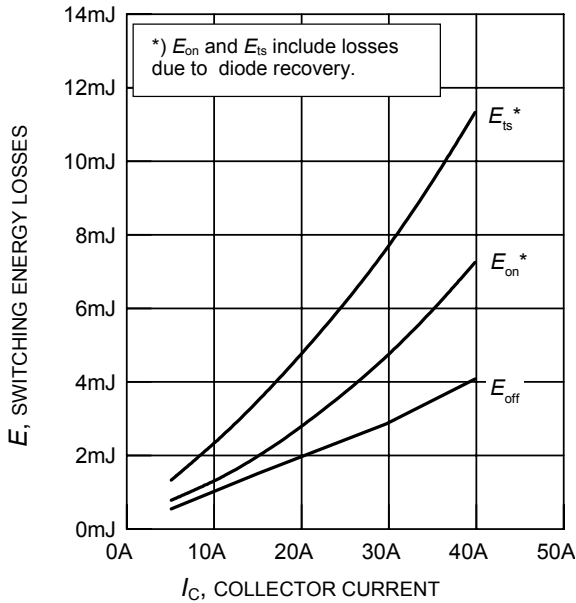
**Figure 11. Typical switching times as a function of junction temperature**

(inductive load,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 15\text{A}$ ,  $R_G = 33\Omega$ , dynamic test circuit in Fig.E )

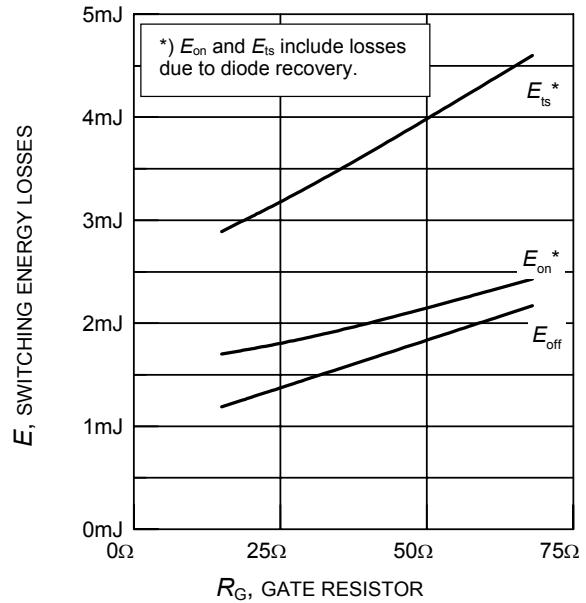


**Figure 12. Gate-emitter threshold voltage as a function of junction temperature**

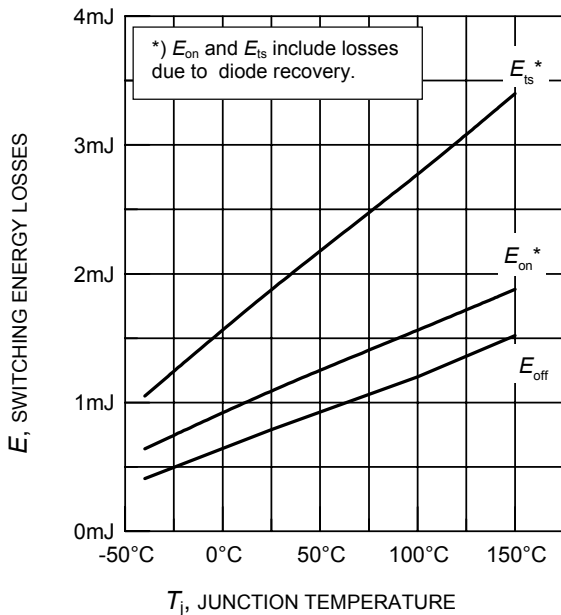
( $I_C = 0.3\text{mA}$ )



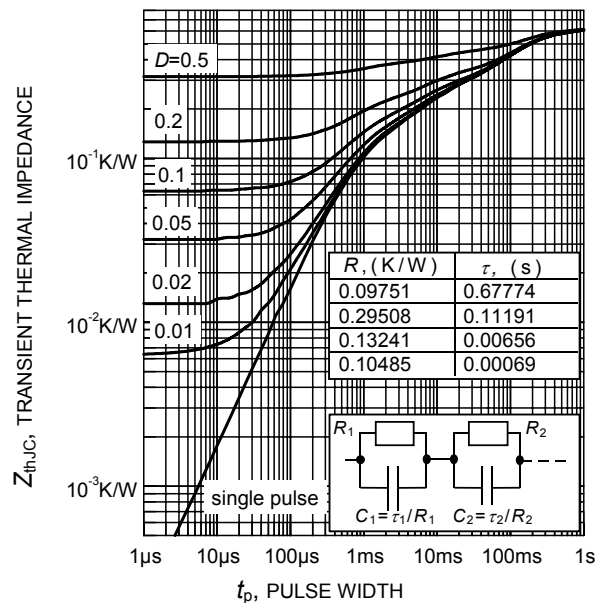
**Figure 13. Typical switching energy losses as a function of collector current**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $R_G = 33\Omega$ , dynamic test circuit in Fig.E )



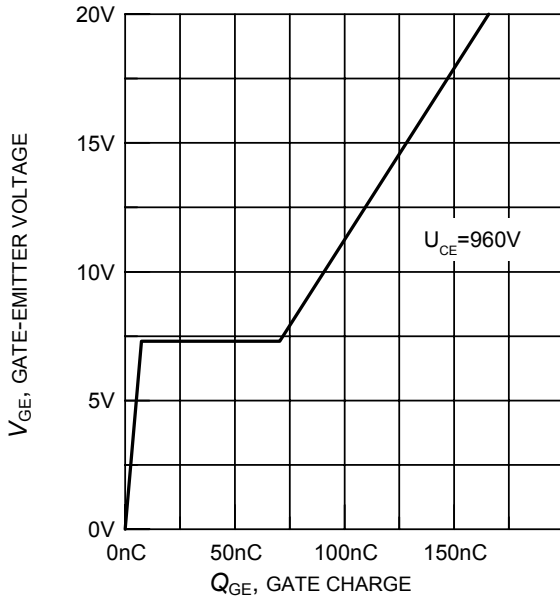
**Figure 14. Typical switching energy losses as a function of gate resistor**  
 (inductive load,  $T_j = 150^\circ\text{C}$ ,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 15\text{A}$ , dynamic test circuit in Fig.E )



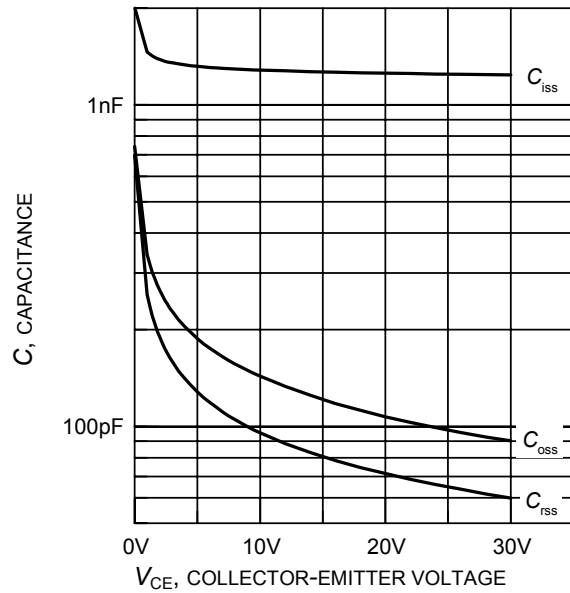
**Figure 15. Typical switching energy losses as a function of junction temperature**  
 (inductive load,  $V_{CE} = 800\text{V}$ ,  $V_{GE} = +15\text{V}/0\text{V}$ ,  $I_C = 15\text{A}$ ,  $R_G = 33\Omega$ , dynamic test circuit in Fig.E )



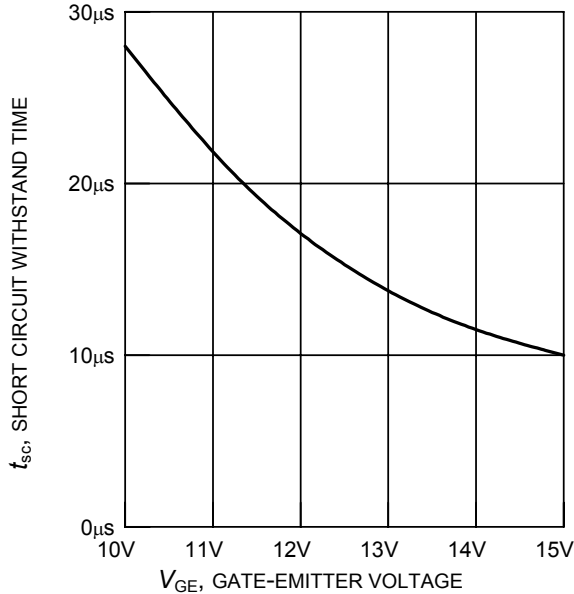
**Figure 16. IGBT transient thermal impedance as a function of pulse width**  
 ( $D = t_p / T$ )



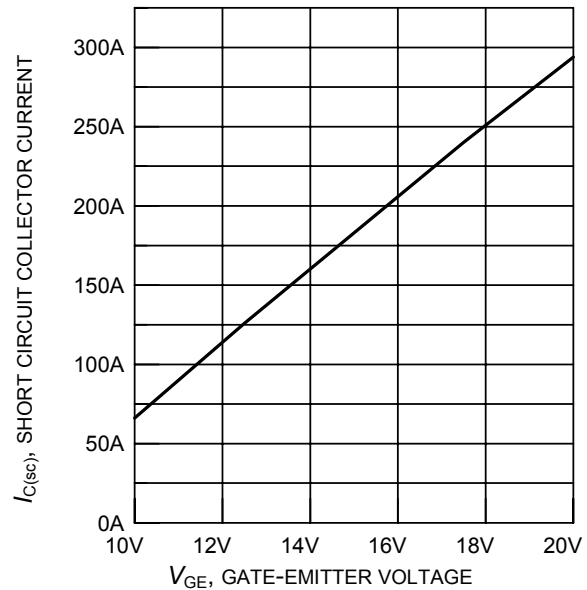
**Figure 17. Typical gate charge**  
( $I_C = 15A$ )



**Figure 18. Typical capacitance as a function of collector-emitter voltage**  
( $V_{GE} = 0V, f = 1MHz$ )



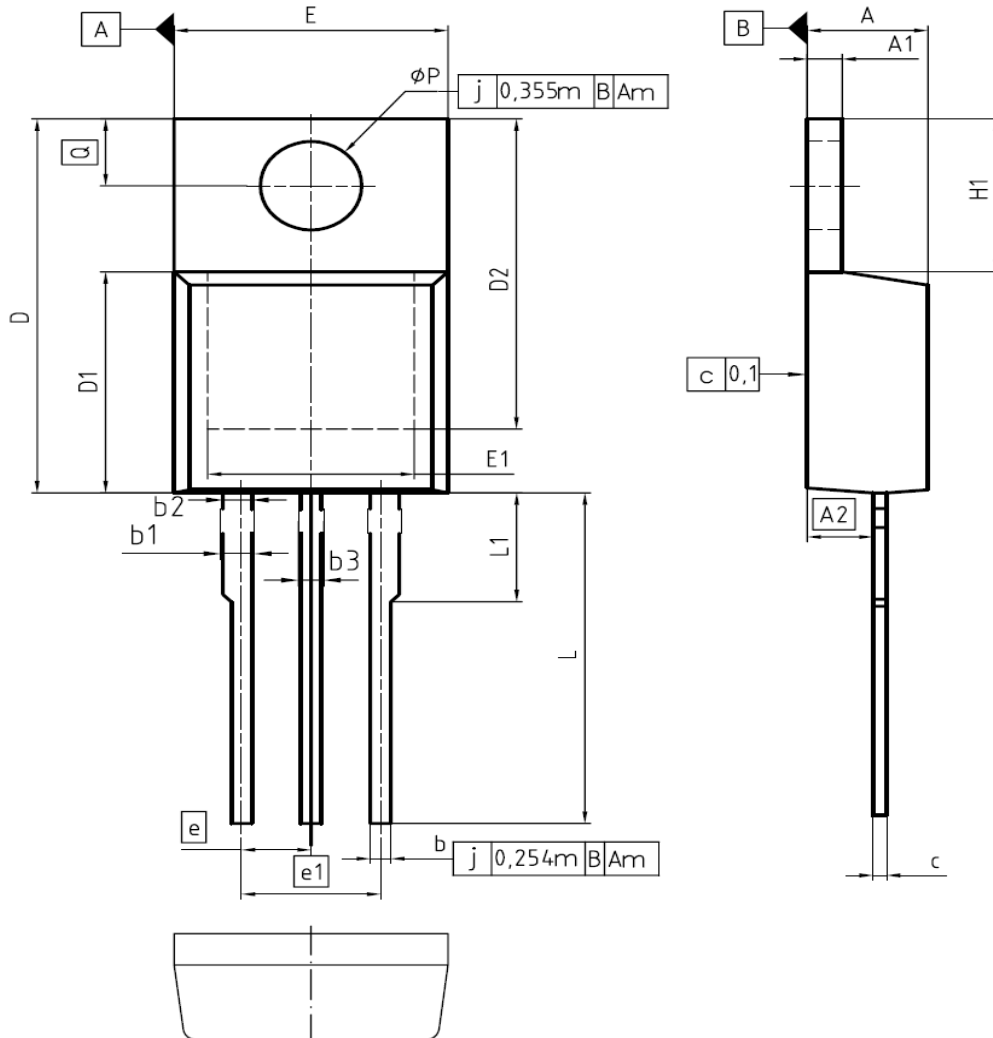
**Figure 19. Short circuit withstand time as a function of gate-emitter voltage**  
( $V_{CE} = 1200V, \text{start at } T_j = 25^\circ C$ )



**Figure 20. Typical short circuit collector current as a function of gate-emitter voltage**  
( $100V \leq V_{CE} \leq 1200V, T_C = 25^\circ C, T_j \leq 150^\circ C$ )



PG-TO220-3-1



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
phi P	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

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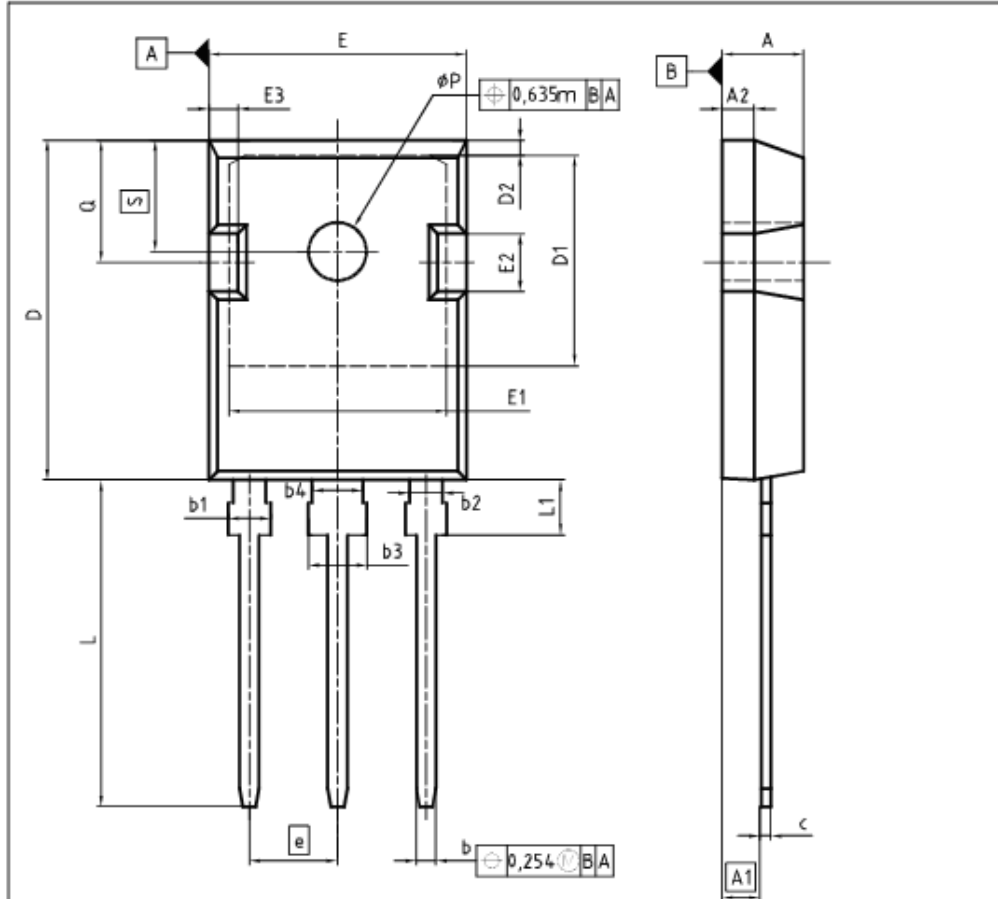
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05

TO247-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.83	5.21	0.190	0.205
A1	2.27	2.54	0.089	0.100
A2	1.85	2.16	0.073	0.085
b	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
c	0.55	0.68	0.022	0.027
D	20.80	21.10	0.819	0.831
D1	16.25	17.65	0.640	0.695
D2	0.95	1.35	0.037	0.053
E	16.70	16.13	0.618	0.635
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.00	2.60	0.039	0.102
e	5.44		0.214	
N	3		3	
L	19.80	20.32	0.780	0.800
L1	4.10	4.47	0.161	0.176
φP	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238	0.248

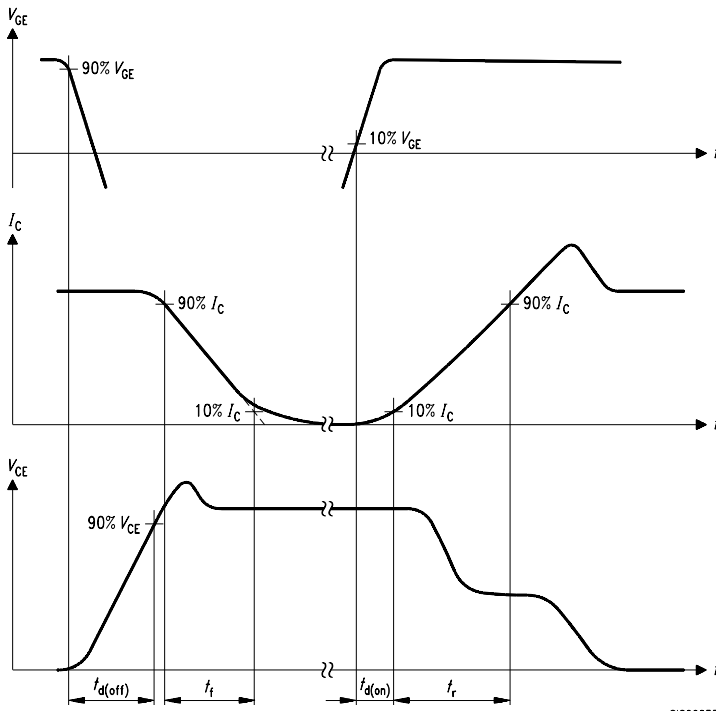
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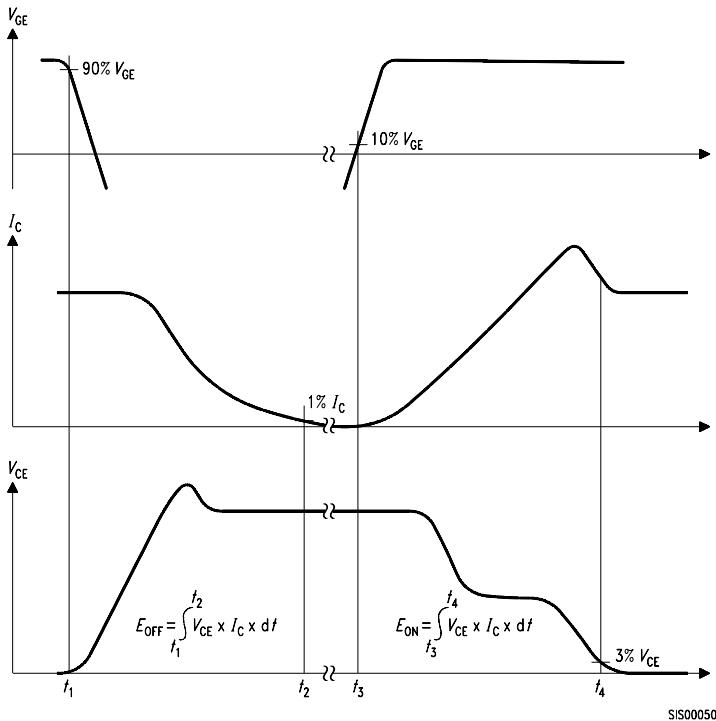
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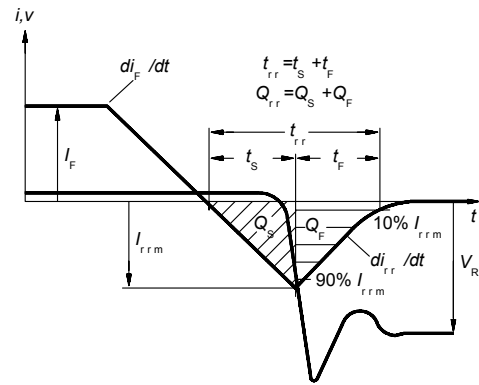
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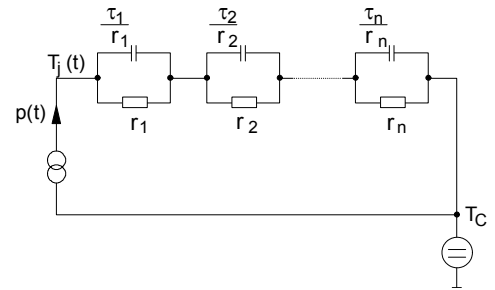
**Figure A. Definition of switching times**



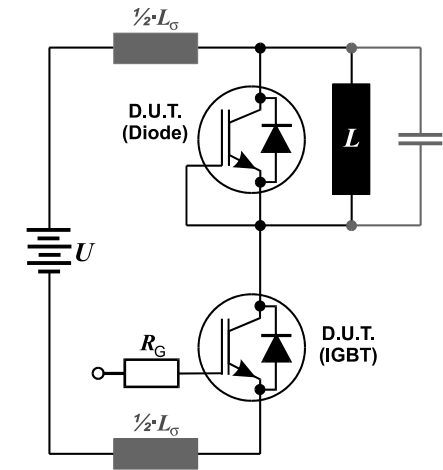
**Figure B. Definition of switching losses**



**Figure C. Definition of diodes switching characteristics**



**Figure D. Thermal equivalent circuit**



**Figure E. Dynamic test circuit**  
Leakage inductance  $L_G = 180\text{nH}$ ,  
and stray capacity  $C_G = 40\text{pF}$ .

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